Search Notes			Application/Control No.  10/602,910  Examiner  David M. Naff		Reexa	Applicant(s)/Patent under Reexamination		
						TAKAYAMA ET AL. Art Unit		
					1651			
	ADOUED				ARCH NOT	ES		
SEARCHED				(INCLUDING SEARCH STRATEGY)			<u>Y)</u>	
Class Subcla	ss Date	Examiner			•	DATE	EXMR	
				intentor Y	nmes	4/28/01	1	
·				West +	+ stn			
			<i></i>					
			. 2	Gdele		(0/30/00	9	
					·- ·· ·			
						[		
					<del></del>			
	· .		•					
INTERFER	ENCE SEARCH	IED						
Class Subcla		Examiner						
<u></u>								